

Schedule of Accreditation

issued by

United Kingdom Accreditation Service

2 Pine Trees, Chertsey Lane, Staines-upon-Thames, TW18 3HR, UK

 4670 Accredited to ISO/IEC 17025:2017	Hi Gain Limited T/A Phasix ESD	
	Issue No: 011 Issue date: 20 January 2025	
	Unit 17 Focus 303 Business Centre Focus Way Andover SP10 5NY	Contact: Carl V R Simon Tel: +44 (0)1264 361622 E-Mail: carl.simon@phasix.co.uk Website: www.phasix.co.uk
Testing performed at the above address only		

DETAIL OF ACCREDITATION

Materials/Products tested	Type of test/Properties measured/Range of measurement	Standard specifications/ Equipment/Techniques used
Packaged electronic components Semi-conductor devices	1 Electrostatic Discharge 1.1 Human Body Model (HBM) Up to 8 kV Using fixtures up to 768 pin for the Mk2 test system No limitation on pins or fixtures applies for the HPPI ATS 8000G system	EIA/JESD22-A114-F:2008 AEC - Q100-002 Rev D:2003 AEC - Q100-002 Rev E:2013 AEC - Q101-001 Rev A:2005 MIL-STD-883G METHOD 3015.7 Excluding section 2.3.2 MIL-STD-883H METHOD 3015.8 Excluding section 2.3.2 MIL-STD-883J METHOD 3015.9 Excluding section 2.3.2 ANSI/ESDA/JEDEC-JS-001-2010 ANSI/ESDA/JEDEC-JS-001-2011 ANSI/ESDA/JEDEC-JS-001-2012 ANSI/ESDA/JEDEC-JS-001-2014 ANSI/ESDA/JEDEC-JS-001-2017 ANSI/ESDA/JEDEC-JS-001-2023 Excluding pin reduction sampling methods
	1.2 Charge Device Model (CDM) Up to 2 kV	AEC - Q100-011 Rev B:2003 AEC - Q100-011 Rev C1:2013 AEC - Q100-011 Rev D:2019 AEC - Q101-005:2005 JESD22-C101C:2004 JESD22-C101D:2008 JESD22-C101E:2009 JESD22-C101F:2013 ANSI-ESDA-JEDEC JS-002-2014 ANSI-ESDA-JEDEC JS-002-2018 ANSI-ESDA-JEDEC JS-002-2022



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Materials/Products tested	Type of test/Properties measured/Range of measurement	Standard specifications/ Equipment/Techniques used
Packaged electronic components Semi-conductor devices (cont'd)	1 Electrostatic Discharge (cont'd) 1.3 Machine model (MM) Up to 2 kV Using fixtures up to 768 pin	EIA/JESD22-A115-A:1997 EIA/JESD22-A115-C:2010 AEC - Q100-003 Rev E:2003 AEC - Q101-002 Rev A:2005
Test Systems	Verifier V2 test system Verifier V3 test system Thermo KeyTek RCDM 3 Thermo Mk. 2 SE/768 test system HPPI ATS 8000 G test system	
END		